

Issue Classification		Application/Control No.	Applicant(s)/Patent under Reexamination
		10/632,079	CHAUVEL ET AL.
Examiner		Art Unit	
Hiep T. Nguyen		2187	

ORIGINAL		CROSS REFERENCE(S)							
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
711	132								
INTERNATIONAL CLASSIFICATION									
G	06	F	121	08					
			/						
			/						
			/						
			/						
				<i>Hiep T. Nguyen</i>					
				HIEP T. NGUYEN				Total Claims Allowed: 20	
				PRIMARY EXAMINER					
				(Primary Examiner) <i>Everett Williams 2-7-06</i>				<i>2/6/06</i> (Date)	
								O.G. Print Claim(s) <i>1</i>	O.G. Print Fig. <i>2</i>

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
1	31	61	91	121	151	167	181
2	32	62	92	122	152	168	182
3	33	63	93	123	153	169	183
4	34	64	94	124	154	170	184
5	35	65	95	125	155	171	185
6	36	66	96	126	156	172	186
7	37	67	97	127	157	173	187
8	38	68	98	128	158	174	188
9	39	69	99	129	159	175	189
10	40	70	100	130	160	176	190
11	41	71	101	131	161	177	191
12	42	72	102	132	162	178	192
13	43	73	103	133	163	179	193
14	44	74	104	134	164	180	194
15	45	75	105	135	165	181	195
16	46	76	106	136	166	182	196
17	47	77	107	137	167	183	197
18	48	78	108	138	168	184	198
19	49	79	109	139	169	185	199
20	50	80	110	140	170	186	200
21	51	81	111	141	171	187	201
22	52	82	112	142	172	188	202
23	53	83	113	143	173	189	203
24	54	84	114	144	174	190	204
25	55	85	115	145	175	191	205
26	56	86	116	146	176	192	206
27	57	87	117	147	177	193	207
28	58	88	118	148	178	194	208
29	59	89	119	149	179	195	209
30	60	90	120	150	180	196	210